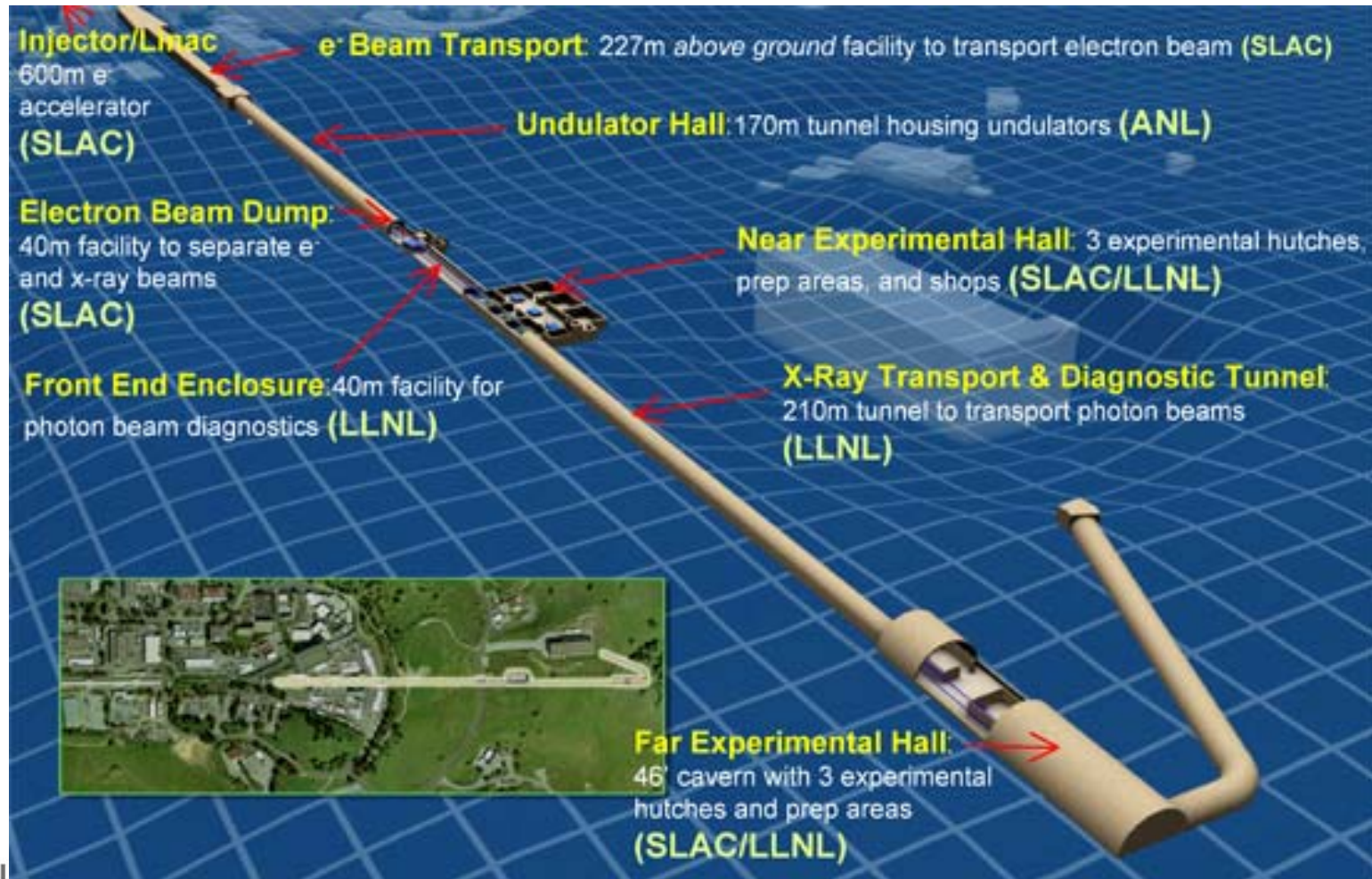


Coherent Diffraction Imaging using X-ray FELs

Ivan Vartanians

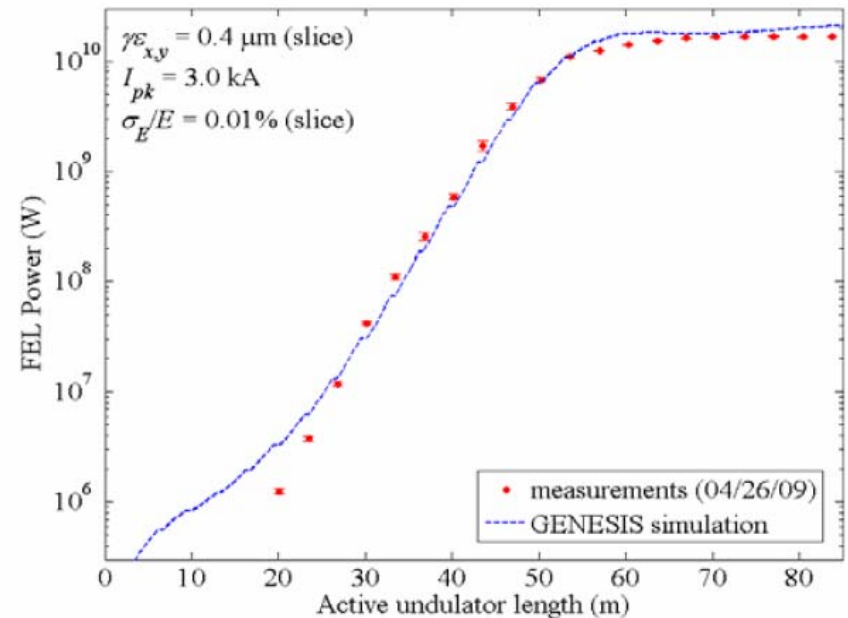
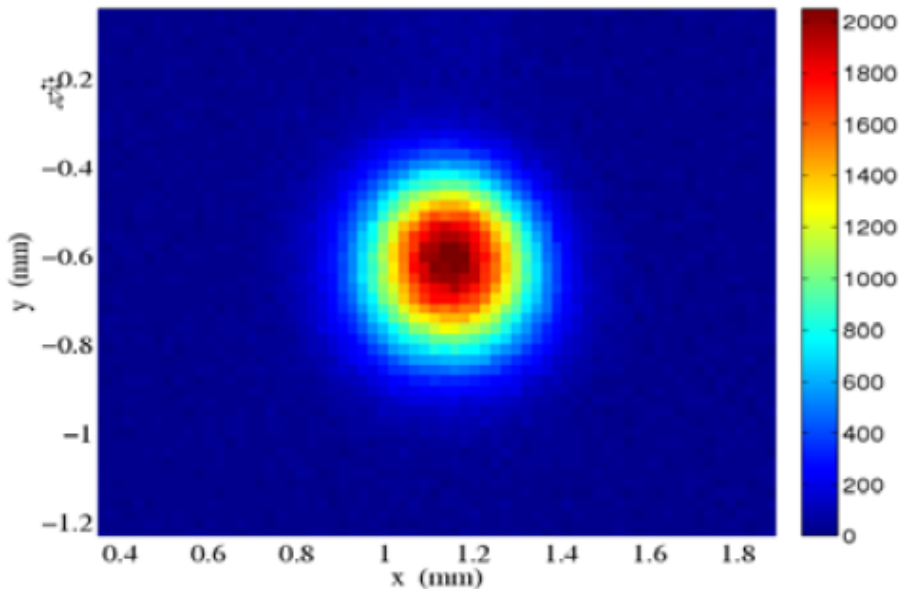
HASYLAB at DESY, Hamburg, Germany

Revolution in X-ray Physics is just happening



Revolution in X-ray Physics is just happening

April 2009



FEL x-rays at 1.5 \AA on a YAG screen 50 m after the last inserted undulator

FEL power gain length measurement (red points) at 1.5 \AA made

1. Introduction

2. Coherent Scattering and Phase Retrieval

3. Coherent X-ray scattering and Imaging in Material Science

- Present status
- Future applications

4. Requirements for Coherent X-ray scattering beamline at XFEL

5. Summary and Outlook

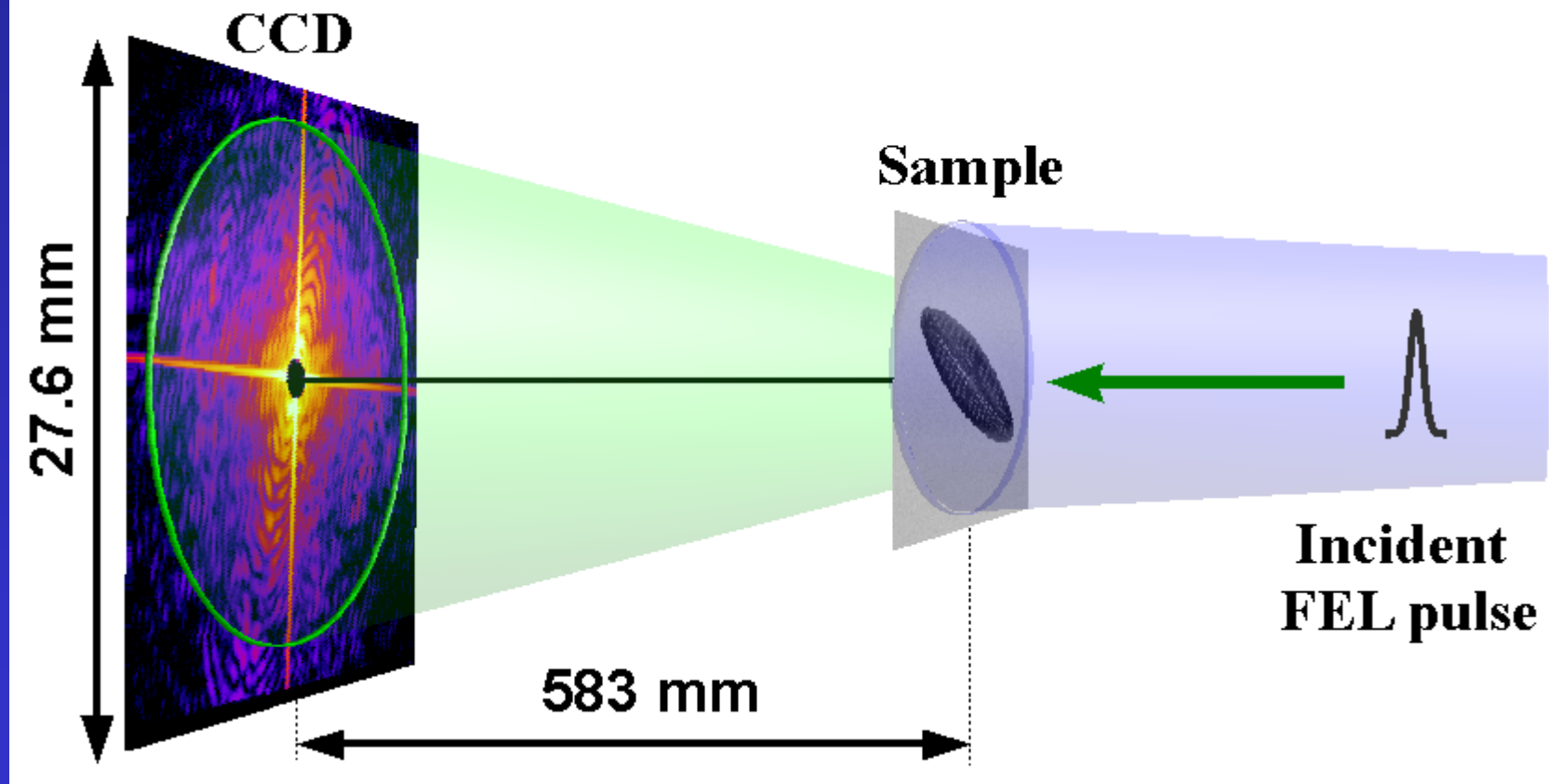


Coherent Scattering and Phase Retrieval

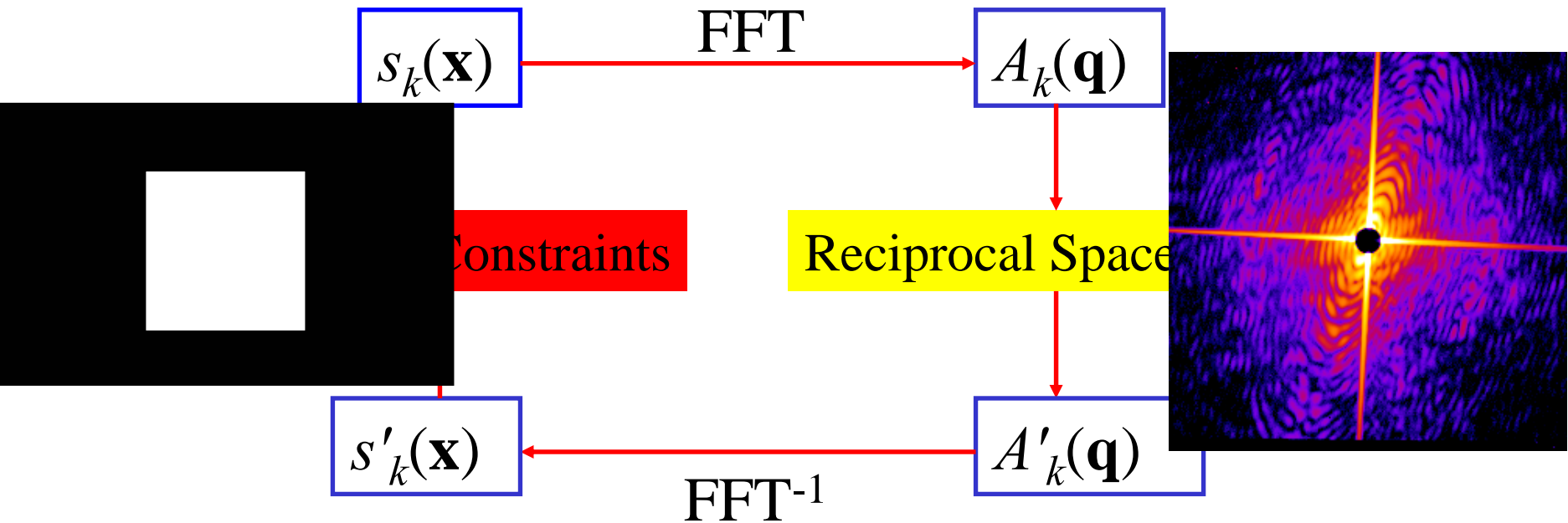


Coherent imaging at FEL sources

CXDI



Iterative phase retrieval algorithm



Real space constraints:

use all *a priori* knowledge:

- finite support
- positivity
- ...

Reciprocal space constraint:

$$|A_k(\mathbf{q})| \rightarrow \sqrt{I_{exp}(\mathbf{q})}$$

R.W.Gerchberg & W.O. Saxton, *Optic* (1972) **35**, 237

J.R. Fienup, *Appl Opt.* (1982) **21**, 2758

V. Elser, *J. Opt. Soc. Am. A* (2003) **20**, 40

CXDI in practice is working well but

CXDI is a photon hungry technique

**We can benefit from the use of
ultrabright pulses of XFEL**



CXDI Experiments at XFEL

Coherent X-ray scattering and lensless imaging in materials science

Coherent X-ray scattering and lensless imaging at the European XFEL Facility

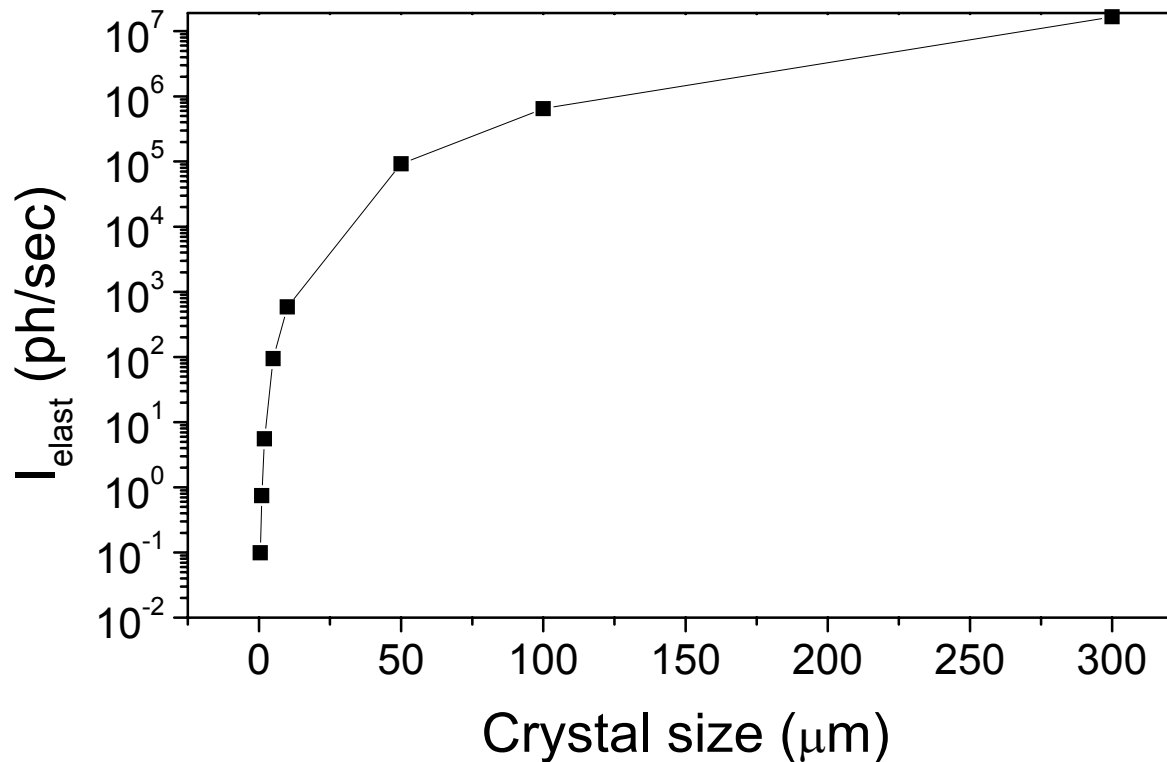
I. A. Vartanyants, I. K. Robinson, I. McNulty, C. David, P. Wochner and Th. Tschentscher

Coherent x-ray scattering and lensless imaging in materials science

Scientific aims

- 3D nanoscale structural analysis using CXDI technique
- main techniques proposed
 - ⇒ **Bragg diffraction for crystalline samples**
 - ⇒ **Forward scattering for non-crystalline objects**
- applications and systems of interest
 - ⇒ **Nanomaterials**
 - properties of single particles (100×100×100 nm³ in single-shot)
 - quantum dots
 - anisotropic strain distribution of single islands (on surface or buried)
 - ⇒ **Mesoscale systems**
 - obtain information about local properties of bulk structures avoiding averaging
 - metals (e.g. dislocations, nucleations) or ceramics (e.g. grain dynamics)
 - ⇒ **Dynamic processes/fluctuations**
 - crystal surface morphology as function of time
 - spontaneous nucleation of clusters
 - crystalline fluctuations in disordered matter
 - ⇒ **Materials properties during processing**
 - precipitates/pores growth or shrinkage
 - welding
 - laser ablation

Nanomaterials



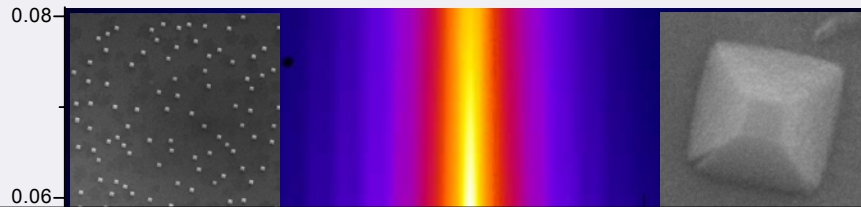
Elastically scattered intensity

incoming flux $I_0=10^{11}$ ph/s \cdot mm 2 , $E=20$ keV

Nanomaterials

(c)

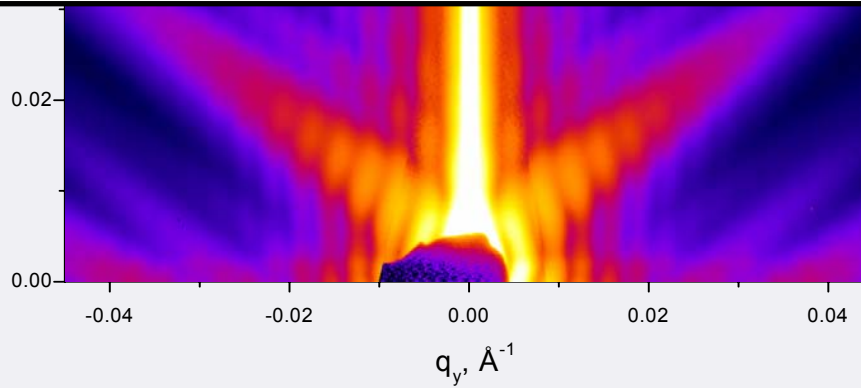
200 nm



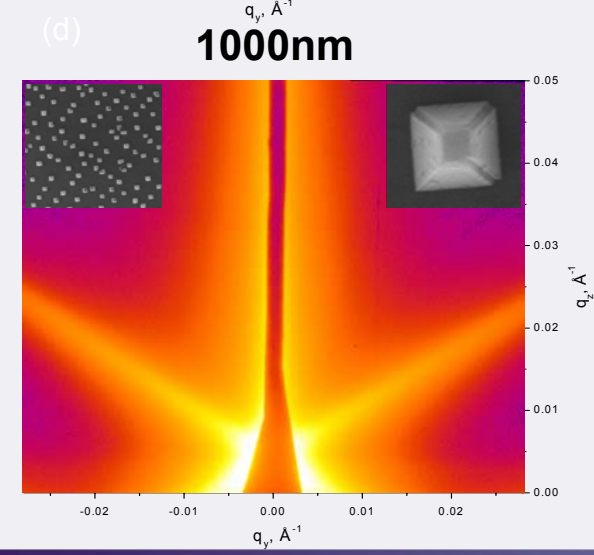
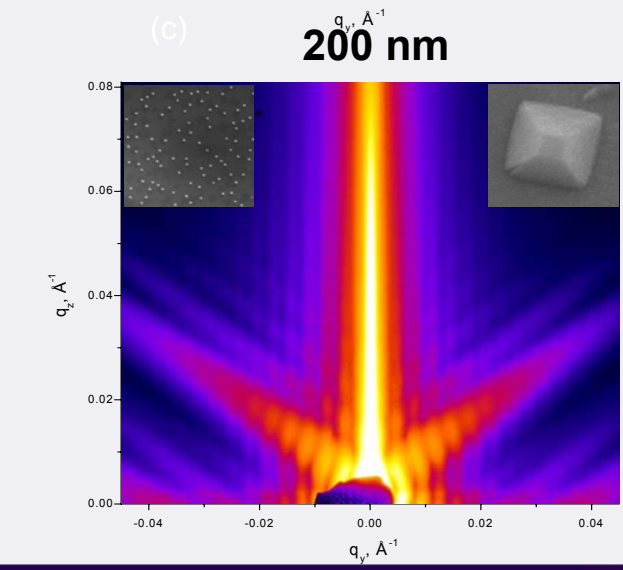
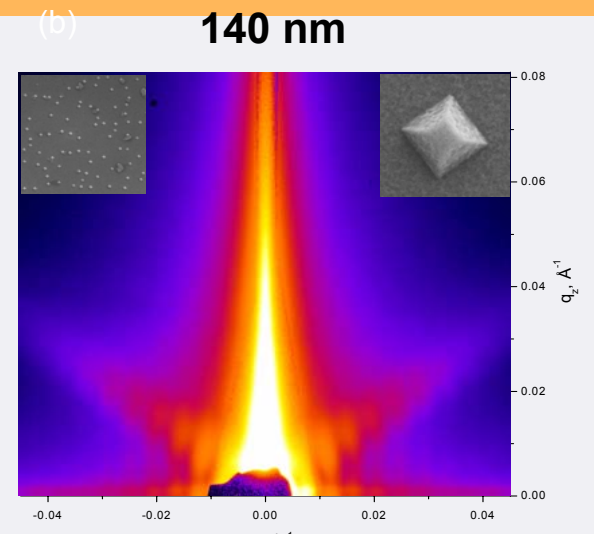
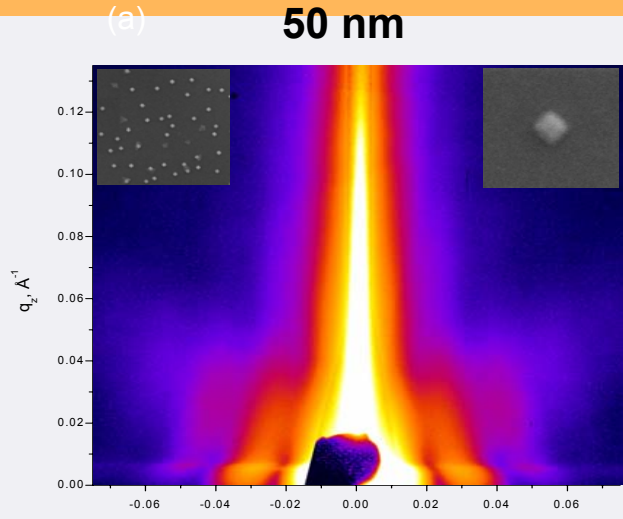
Coherent GISAXS scattering

XFEL

pushing the limits to 10 nm and below



Coherent GISAXS Measurements



Results of reconstruction



Extension to XFEL is straightforward

**Time- dependent studies (reactions,
oxidation, *etc.*)**

An estimate of resolution: **10-15 nm !**

Not accessible by any other X-ray methods

Extension to XFEL

Scattered intensity for a narrow size distribution:

$$I(\mathbf{q}) = NI_{av}^{coh}(\mathbf{q}) \left[1 + \frac{1}{N} \sum_{i \neq j} \exp[i\mathbf{q}(\mathbf{R}_i - \mathbf{R}_j)] \right]$$

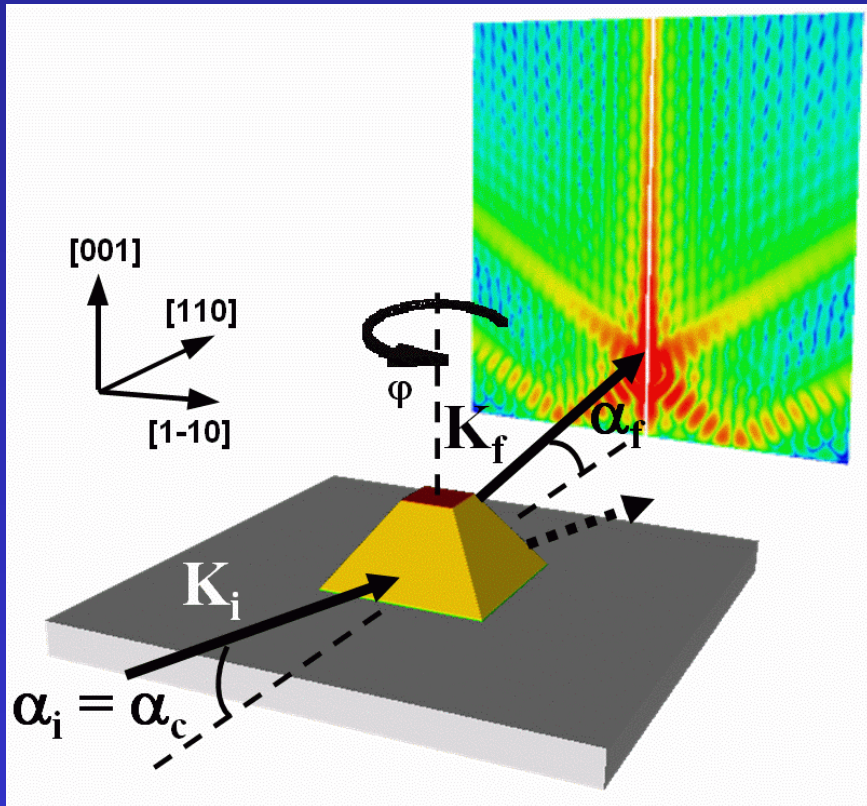
Experimental parameters for each sample during measurements

Sample	Average island size, nm	No. of illuminated islands, $N_{islands}$	Average distance, nm	Incoming flux, ph/s	Total incoming flux, ph	Incoming flux per averaged island, ph/s	Total incoming flux per averaged island, ph	Incoming flux per averaged island $\times N_{islands}$, ph/s	Total incoming flux per averaged island $\times N_{islands}$, ph
1	50	$3.5 \cdot 10^7$	200	$7.5 \cdot 10^{11}$	$5.4 \cdot 10^{15}$	$2.5 \cdot 10^2$	$1.8 \cdot 10^6$	$8.7 \cdot 10^9$	$6.3 \cdot 10^{13}$
2	140	$4.7 \cdot 10^6$	650	$3 \cdot 10^{12}$	$7.8 \cdot 10^{15}$	$2 \cdot 10^3$	$5.2 \cdot 10^6$	$9.4 \cdot 10^9$	$2.4 \cdot 10^{13}$
3	200	$2.5 \cdot 10^6$	900	$3 \cdot 10^{12}$	$1.2 \cdot 10^{16}$	$4 \cdot 10^3$	$1.6 \cdot 10^7$	$1 \cdot 10^{10}$	$4 \cdot 10^{13}$
4	1000	$7.2 \cdot 10^5$	2400	$1 \cdot 10^{12}$	$3.6 \cdot 10^{14}$	$1 \cdot 10^5$	$3.6 \cdot 10^7$	$7.2 \cdot 10^{10}$	$2.6 \cdot 10^{13}$

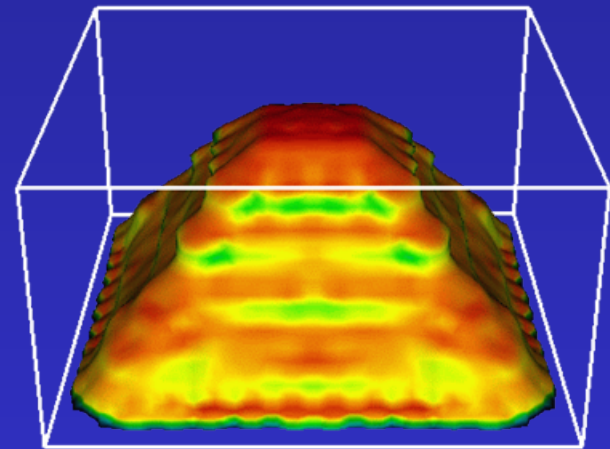
Extension to 3D imaging?



Coherent X-ray Diffraction Tomography



Incident angle: $\alpha_i = \alpha_c = 0.22^\circ$
Saxs tube: CCD at 2 meters
Azimuthal scan ω : 1° steps



Reconstructed shape
of an island

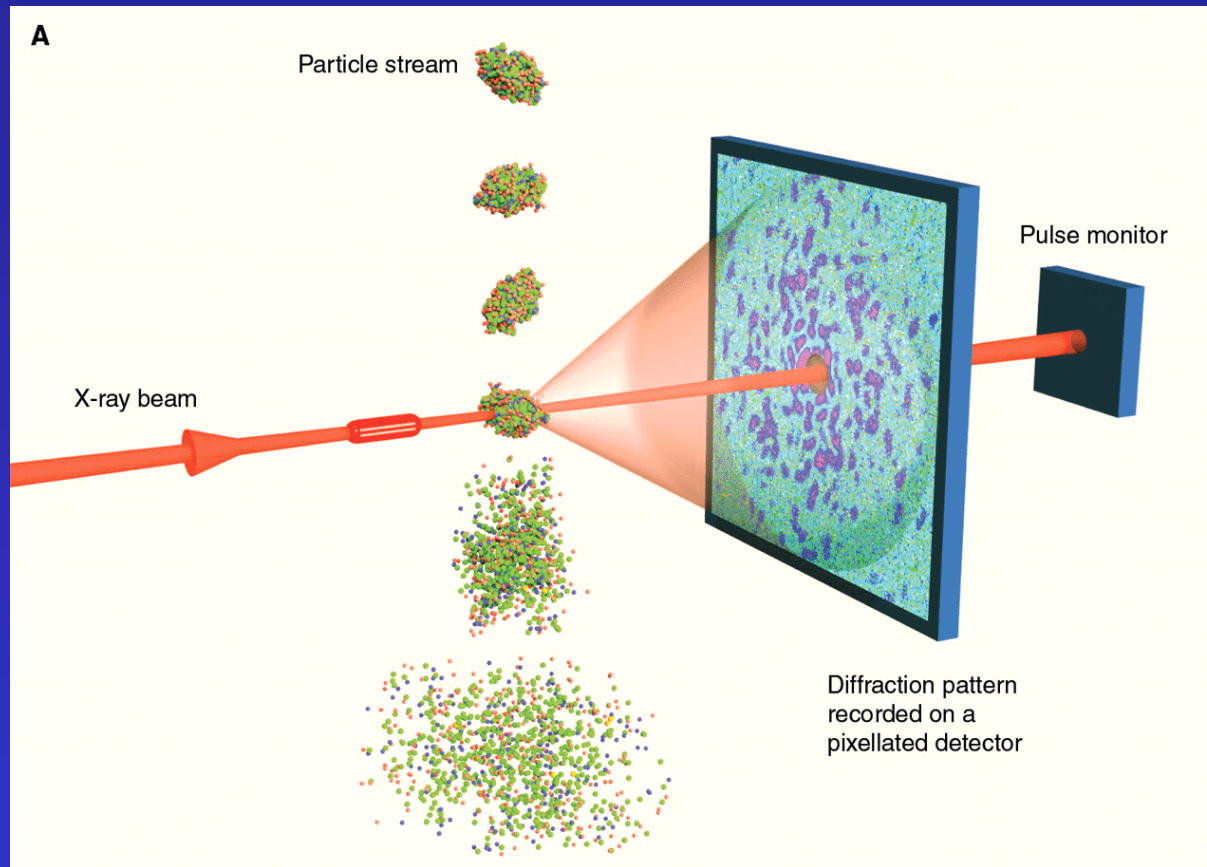
Imaging of Biological samples with XFEL

Low scattered signal

Radiation damage



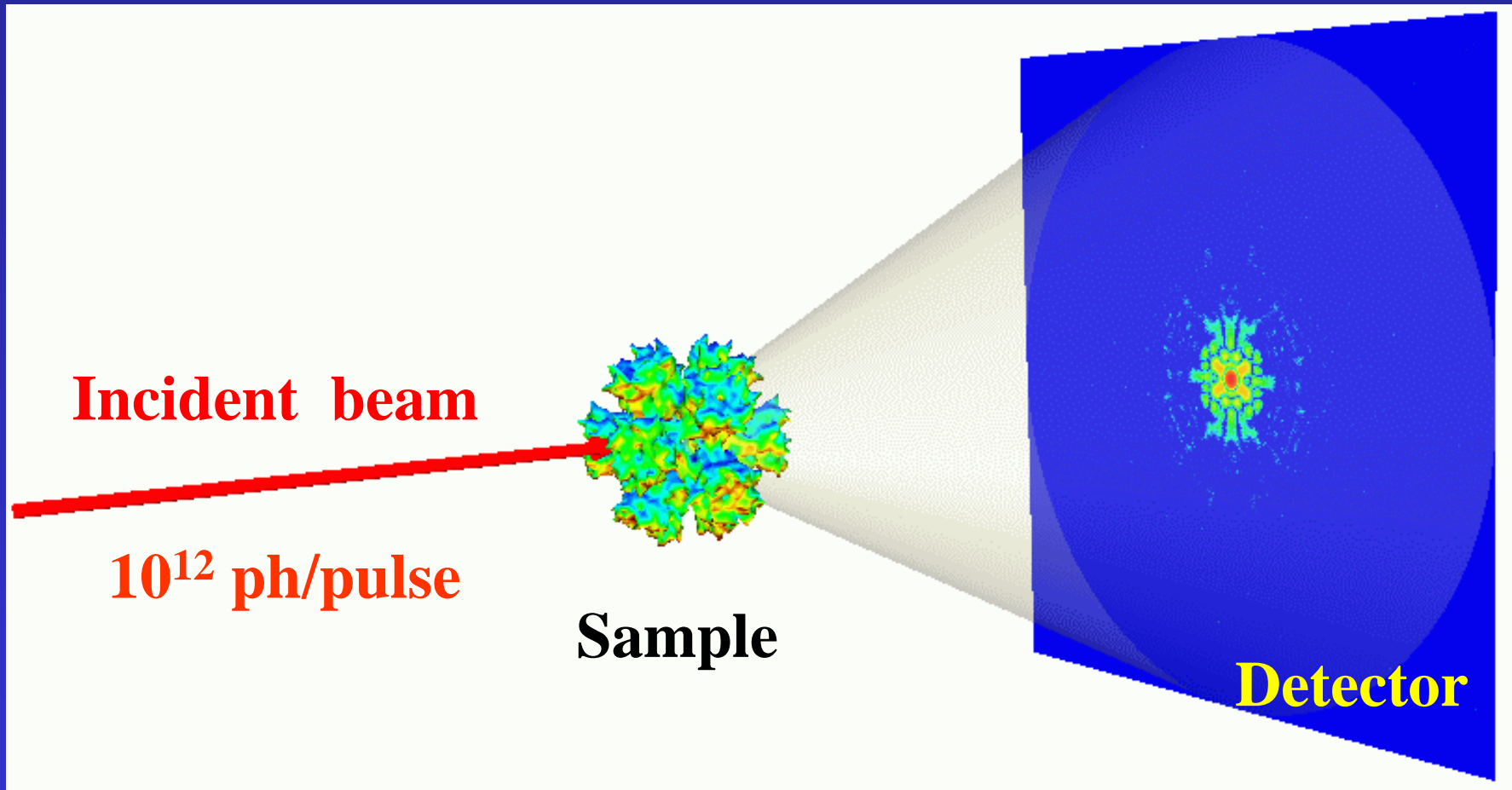
Imaging of biomolecules with femtosecond X-ray pulses



An elegant idea is based on measuring a sufficiently sampled diffraction pattern from a *series of injected* biological samples (viruses, molecules)

K. J. Gaffney and H. N. Chapman, Science (2007)

Imaging of biomolecules with femtosecond X-ray pulses



Single shot will produce a low resolution
noisy image

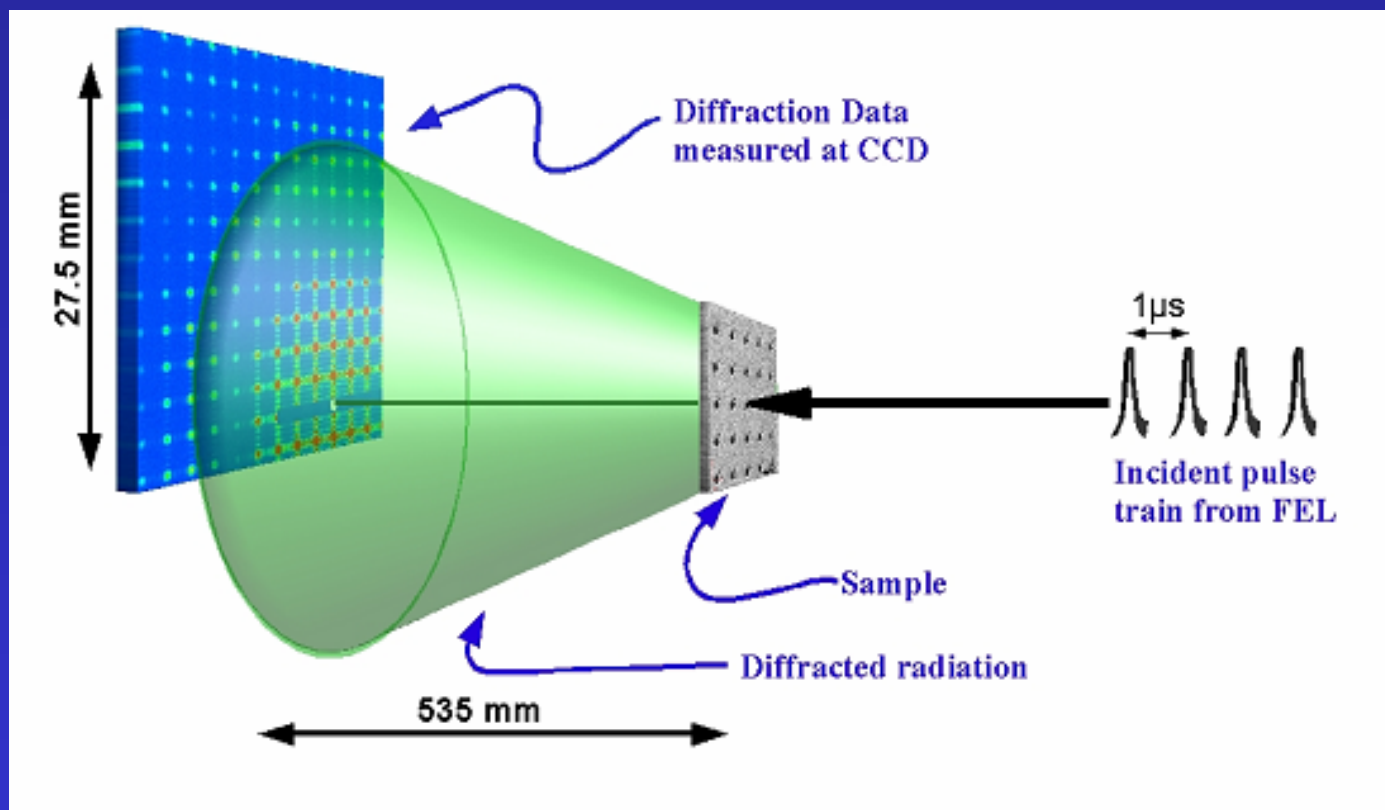
FLASH Facility at DESY



- **Jan 2005** first lasing at 32 nm
- **Aug 2005** start of user experiments
- **Energy range** ~0.3 - 1GeV
→ ~6.5 - 60 nm (~20-200 eV)
- **Peak power** 1-10 GW
- **Pulse duration** <100 fs
- **Bandwidth $\Delta\lambda/\lambda$** ~0.5 %

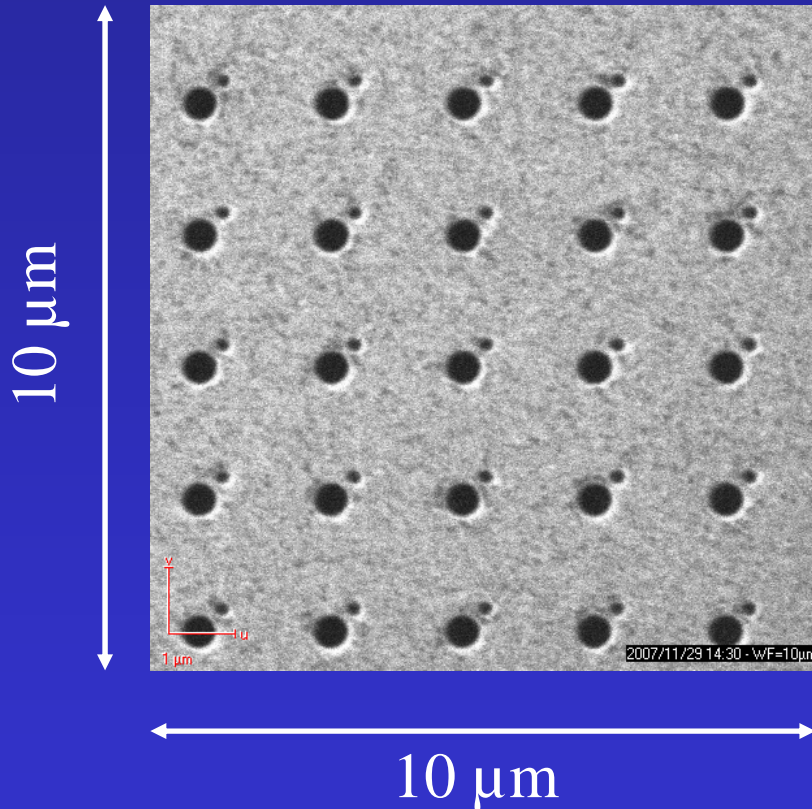
Coherent-pulse 2D Crystallography at FEL

measurements at fundamental 7.97 nm

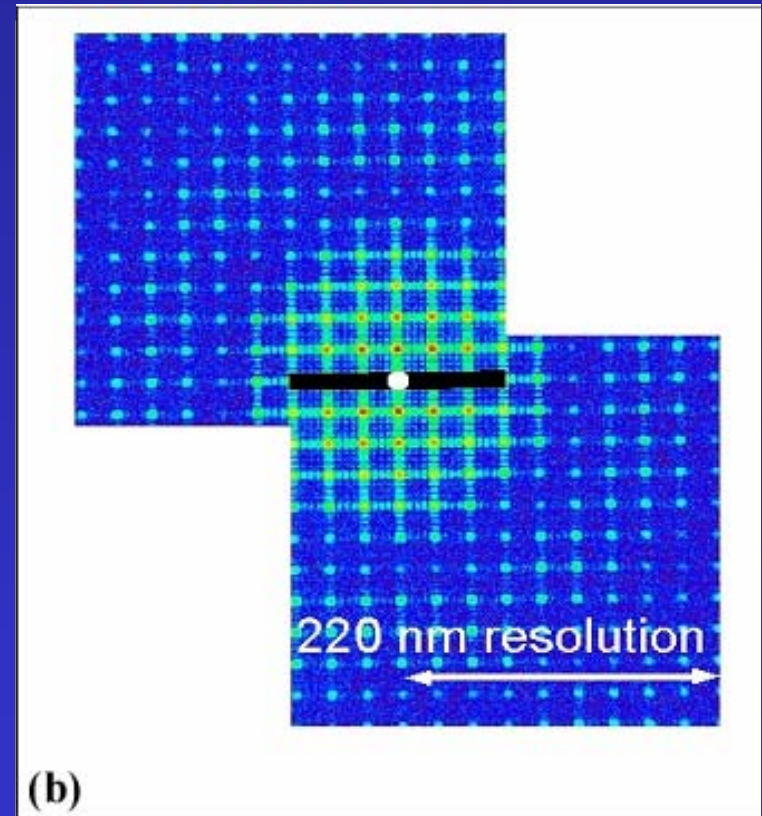


Scheme of experiment

Coherent-pulse 2D Crystallography at FEL



Sample: prepared by FIB



Symmetrized Diffraction Pattern

Coherent-pulse 2D Crystallography at FEL

By using periodic array: we increase signal to noise ratio

$$S / N \sim \sqrt{N_{uc}}$$

Conditions of experiment

- beam size on the sample position: $150 \times 150 \mu\text{m}^2$
- flux: 4.5×10^{10} ph/pulse
- coherent flux on the sample area (0.2 sec):
 1.5×10^{10} ph/pulse train

**This is at least one order of magnitude
higher than at the 3rd generation
synchrotron sources**

How to get an ultimate resolution?

Recipe:

- **To increase signal to noise ratio**
- **To break the symmetry**

Result of reconstruction

Increased signal to noise ratio
due to 5×5 times binning

Extension to XFEL is straightforward

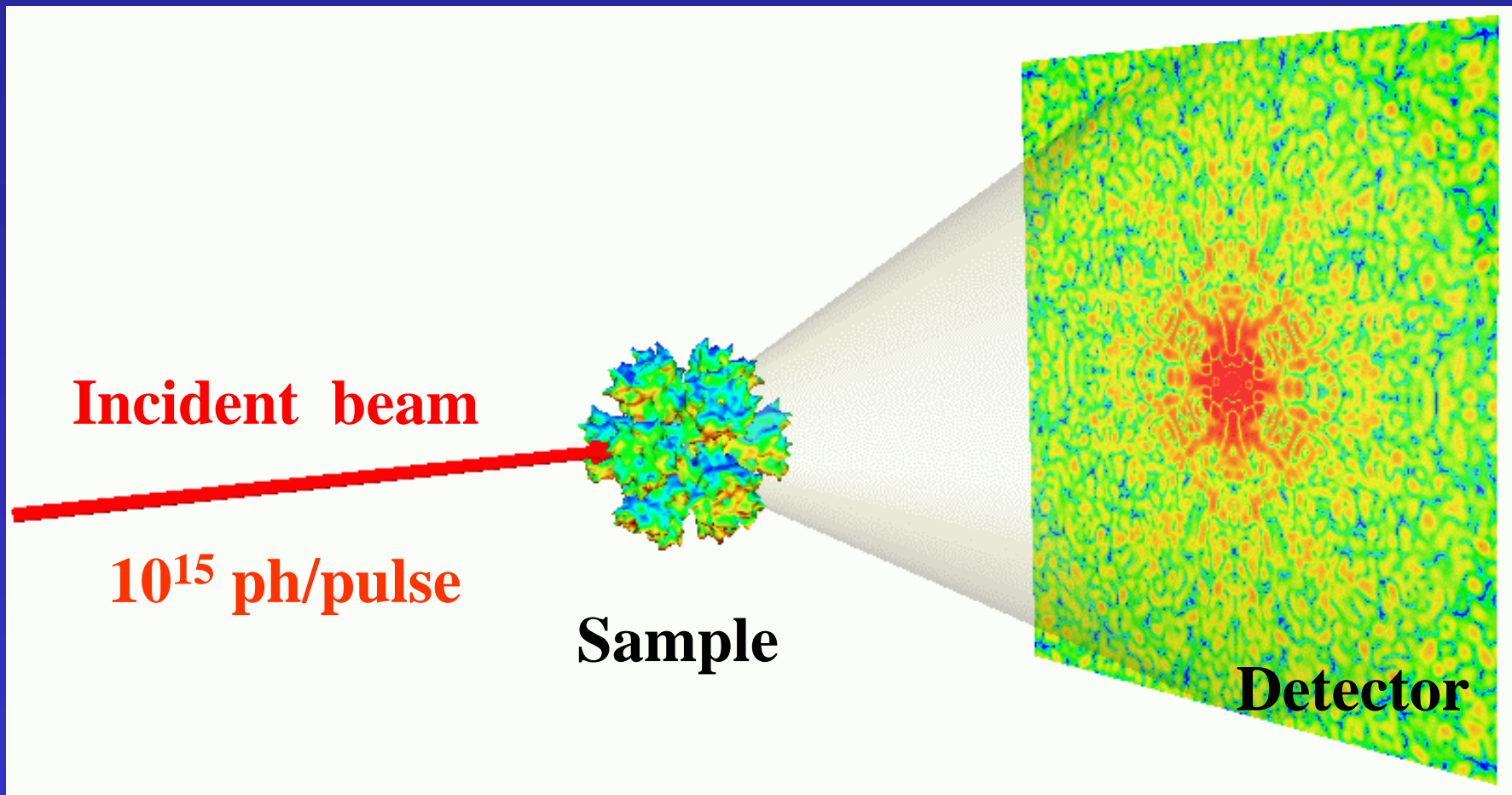
**2D crystallography at shorter
wavelengths with single FEL pulses**

Support used in
reconstruction

Reconstructed Image

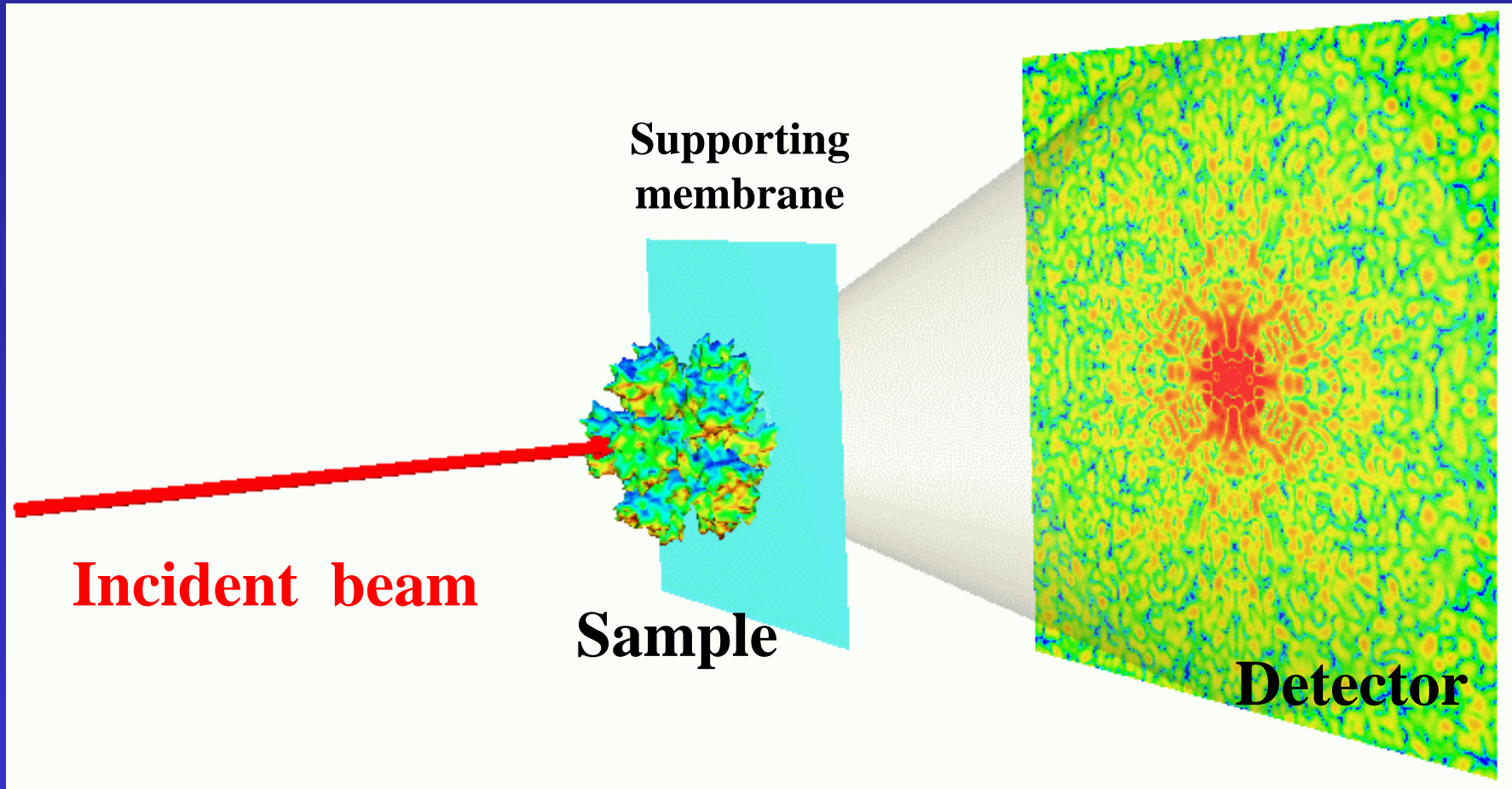
Resolution estimate: 220 nm

Imaging of biomolecules with femtosecond X-ray pulses ⁷



To obtain a 3D image of biological samples with sub-nanometer resolution many *reproducible* copies will need to be measured

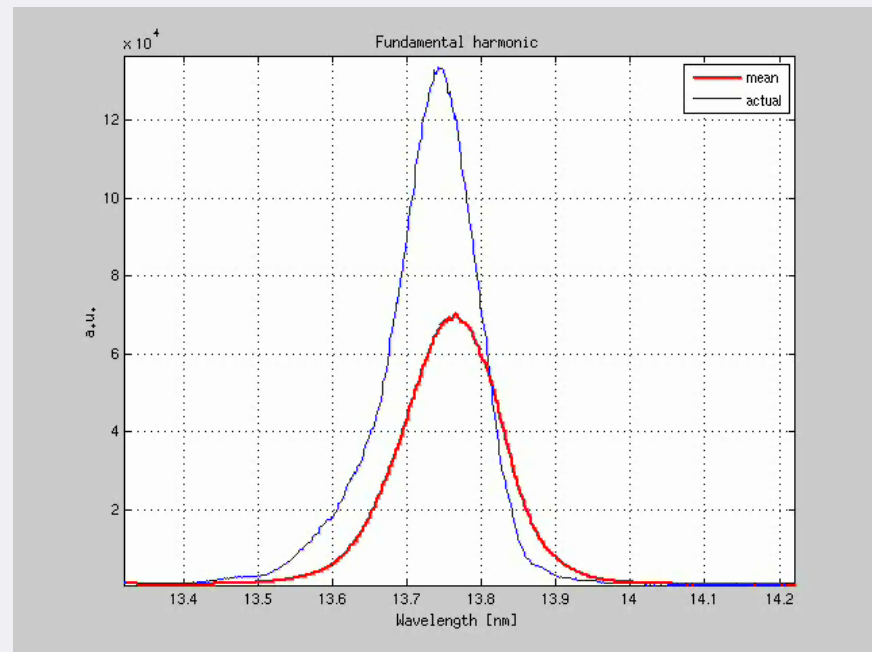
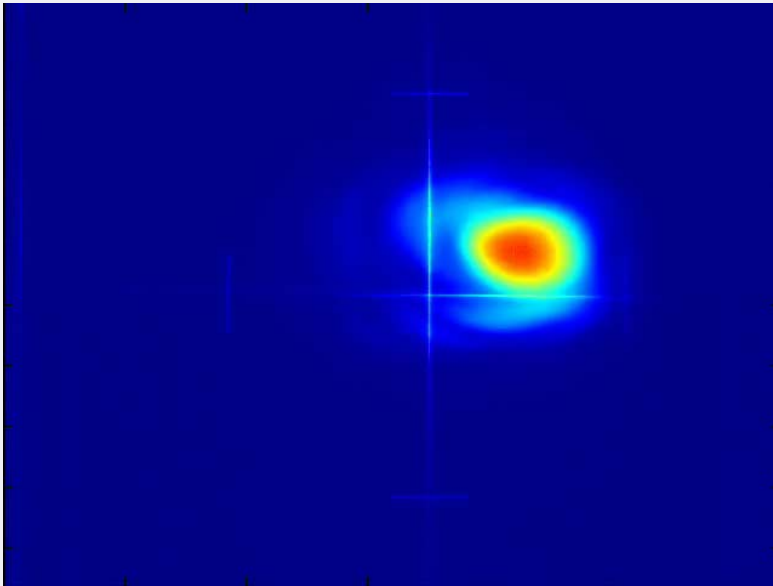
Imaging of biomolecules with femtosecond X-ray pulses ⁷



For *non-reproducible* biological samples (e.g. cells) supported on the membrane same 2D projection of electron density will be measured as for injected particles

SASE: Shot to Shot Fluctuations

Spectral distribution at 13,7 nm



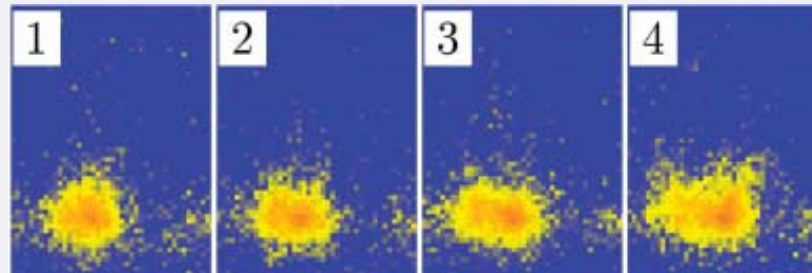
W. Ackermann et al.

Operation of a free-electron laser from the extreme ultraviolet to the water window

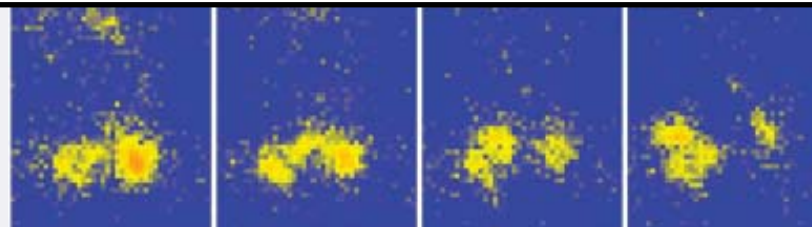
Nature Photonics 1, 336 (2007)

Study of the Early Stages of Protein Crystallization

Ferritine crystal
measured at
room temperature



XFEL
pushing time resolution limits
to 100 fs



Evolution of a Bragg peak over time.
Each image is taken **95 s** apart.

Requirements for Coherent X-ray Scattering beamline at European XFEL

Coherent x-ray imaging – Instrument requirements

Requirements

- solid samples
- tunable soft x-ray FEL radiation
- hard x-ray FEL radiation
- high energy spontaneous radiation
- large area detectors

X-ray beam requirements

- ● photon energy
 - ⇒ 0.5 – 1.0 keV (transition metal L)
 - ⇒ (3)8-12 keV (surfaces & bulk)
 - ⇒ 60-90 keV (hard materials)
 - ⇒ bw 10^{-4} - 10^{-3} (long. coherence)
- ● beam size
 - ⇒ 100-1000 nm
- ● time domain
 - ⇒ 10 Hz rep. rate
 - ⇒ Pulse trains for 200 ns timescale
 - ⇒ 10 fs synchronisation

Instrumentation

- ● photon diagnostics
 - ⇒ photon flux, coherence/wavefront, spectral distribution
- sample manipulation & environment
 - ⇒ UHV conditions
 - ⇒ solid samples
 - ⇒ fast exchange and sample alignment (~1 μ m)
 - ⇒ surface preparation techniques
- ● detector requirements
 - ⇒ x-ray area detectors covering a large portion of reciprocal space

Coherence at European XFEL

Is it a fully coherent source?

I. Vartaniants, A. Singer, DESY Preprint, DESY 09-114 (2009)



General Theoretical Approach

based on Statistical Optics

Mutual coherence function:

$$\Gamma(\mathbf{r}_1, \mathbf{r}_2, \tau) = \langle E(\mathbf{r}_1, t)E(\mathbf{r}_2, t + \tau) \rangle$$

Cross-spectral density function:

$$W(\mathbf{r}_1, \mathbf{r}_2, \omega) = \int_{-\infty}^{\infty} \Gamma_{12}(\tau) e^{-i\omega\tau} d\tau$$

CSD of a partially coherent field can be represented as a sum of independent coherent modes

$$W(\mathbf{r}_1, \mathbf{r}_2) = \sum_{j=0} \beta_j \psi_j^*(\mathbf{r}_1) \psi_j(\mathbf{r}_2)$$

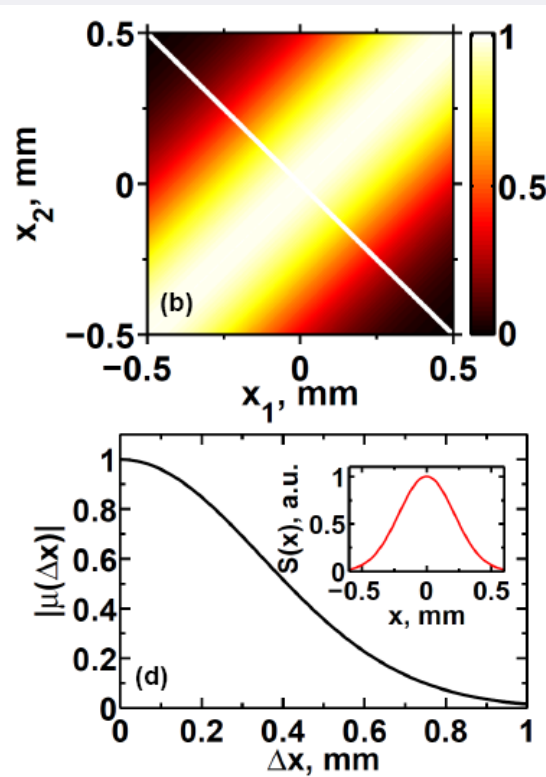
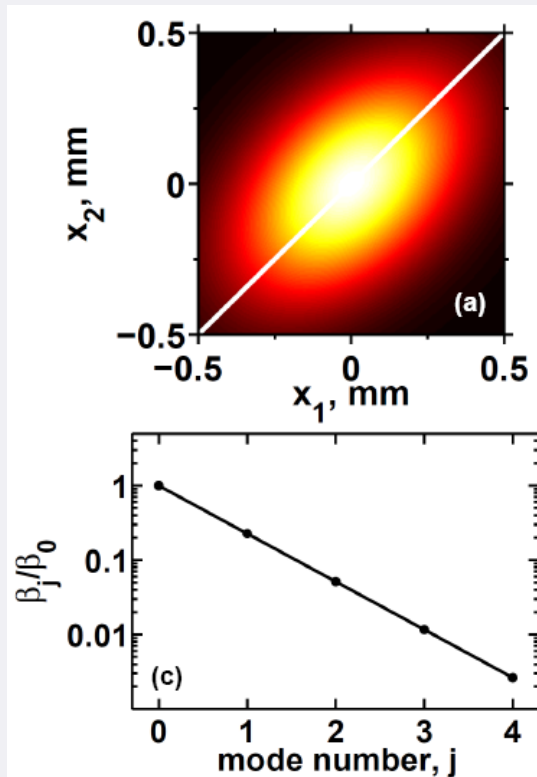
β_j and $\psi_j(\mathbf{r})$ are the eigenvalues and eigenfunctions that satisfy Fredholm integral equation

$$\int W(\mathbf{r}_1, \mathbf{r}_2) \psi_j(\mathbf{r}_1) d\mathbf{r}_1 = \beta_j \psi_j(\mathbf{r}_2)$$

Calculations for European XFEL

$$|W(x_1, x_2)|$$

$$|\mu(x_1, x_2)|$$



Parameters of European XFEL
for SASE I undulator:

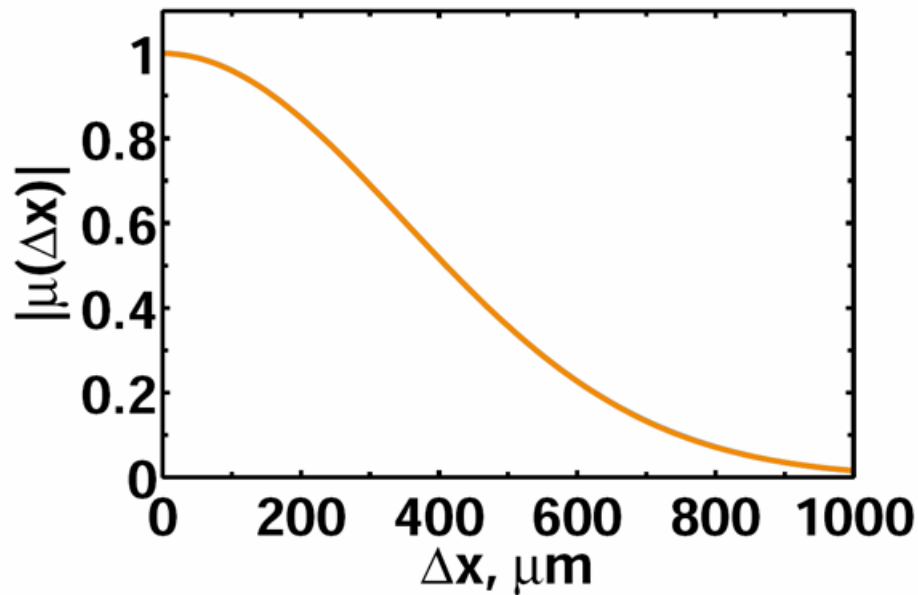
($E=12$ keV, $z=500$ m)

$\sigma=30 \mu\text{m}$
 $\sigma'=0.42 \mu\text{rad}$

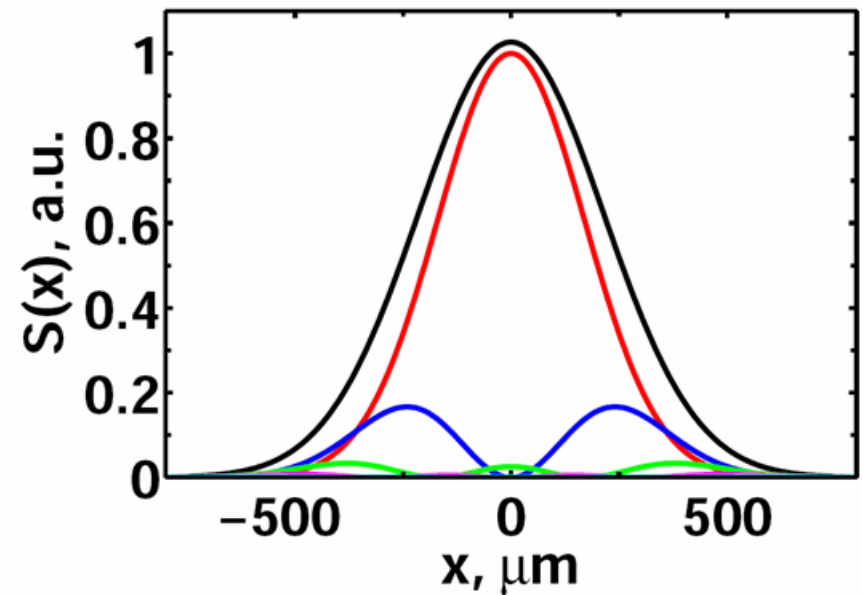
Degree of coherence: 63%

Contribution of each mode

Complex degree of coherence

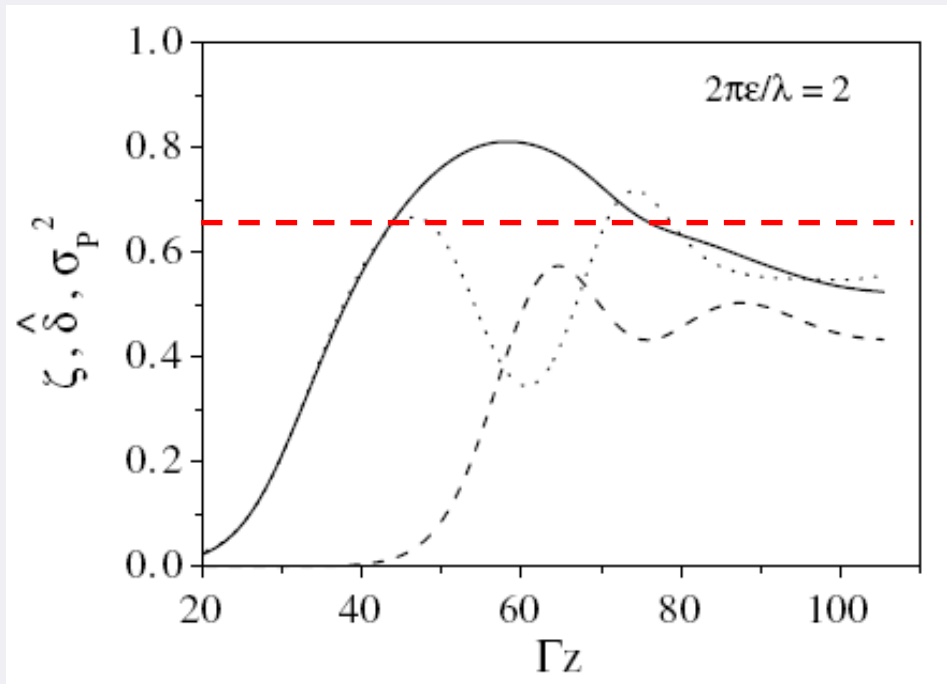


Spectral density



Five modes

Transverse Coherence of XFEL



$$\gamma(\mathbf{r}, \mathbf{r}') = \frac{\langle E(\mathbf{r}, t) E(\mathbf{r}', t) \rangle}{\sqrt{I(\mathbf{r}, t)} \sqrt{I(\mathbf{r}', t)}}$$

$$\zeta = \frac{\int |\gamma(\mathbf{r}, 0)|^2 I(\mathbf{r}) d\mathbf{r}}{\int I(\mathbf{r}) d\mathbf{r}}$$

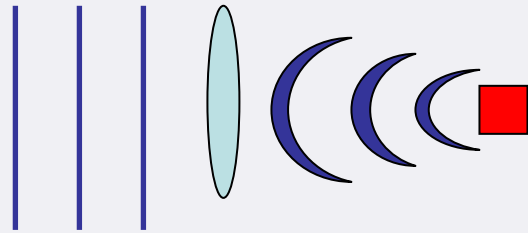
Degree of coherence: 65%

Degree of transverse coherence in SASE1 is mainly limited by the contribution of higher radiation modes

Optics

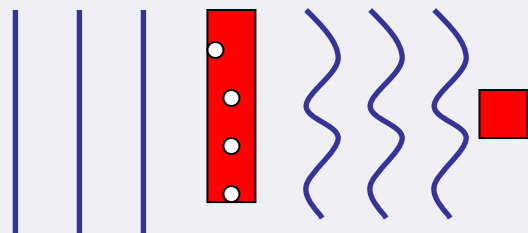


Optics in Coherent X-ray beam



Controlled change of the wavefront
(known additional phase)

'Perfect' or Diffraction Limited Optics

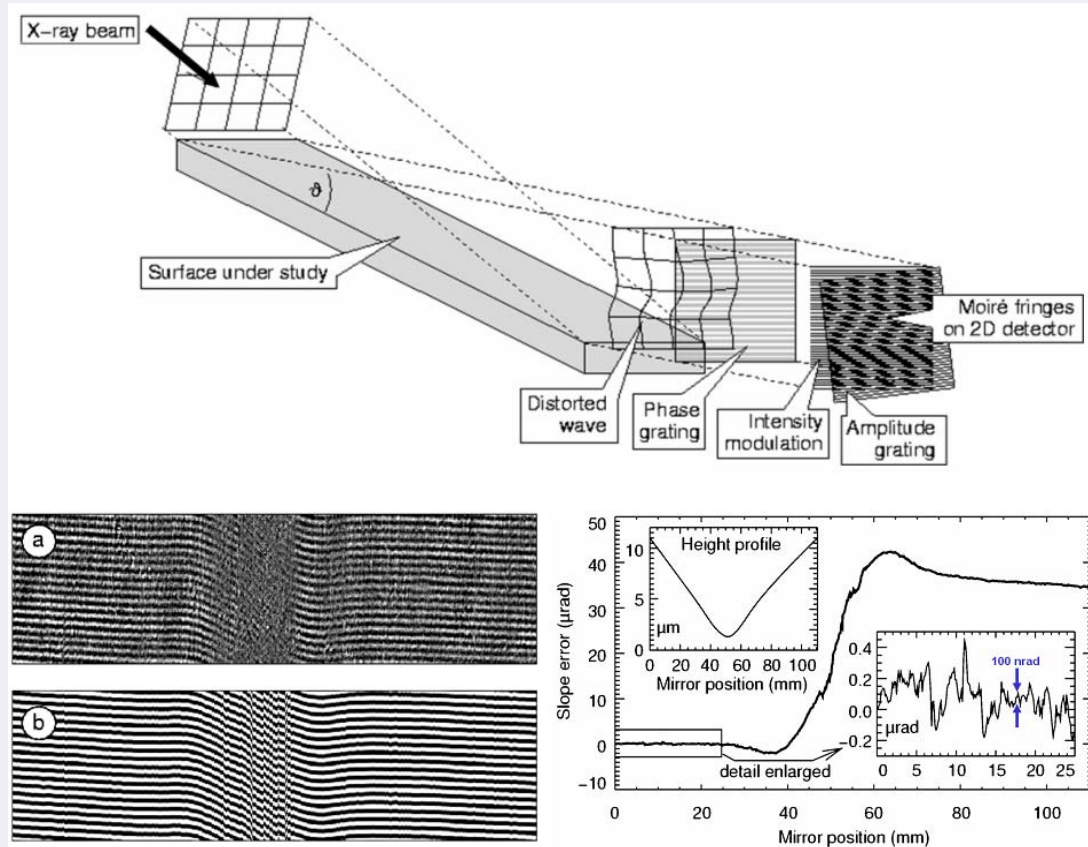


Uncontrolled change of the
wavefront
(unknown phase)

Artifacts in reconstruction

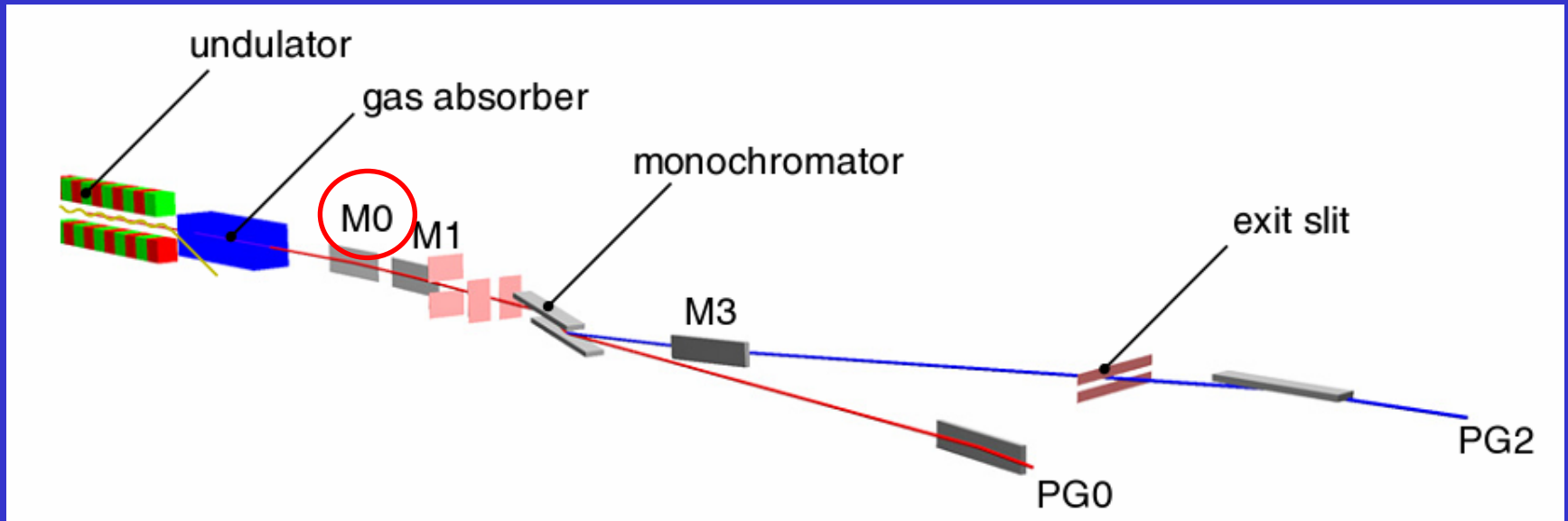
Non Perfect Optics

Coherence or Wave Front Preserving Optics



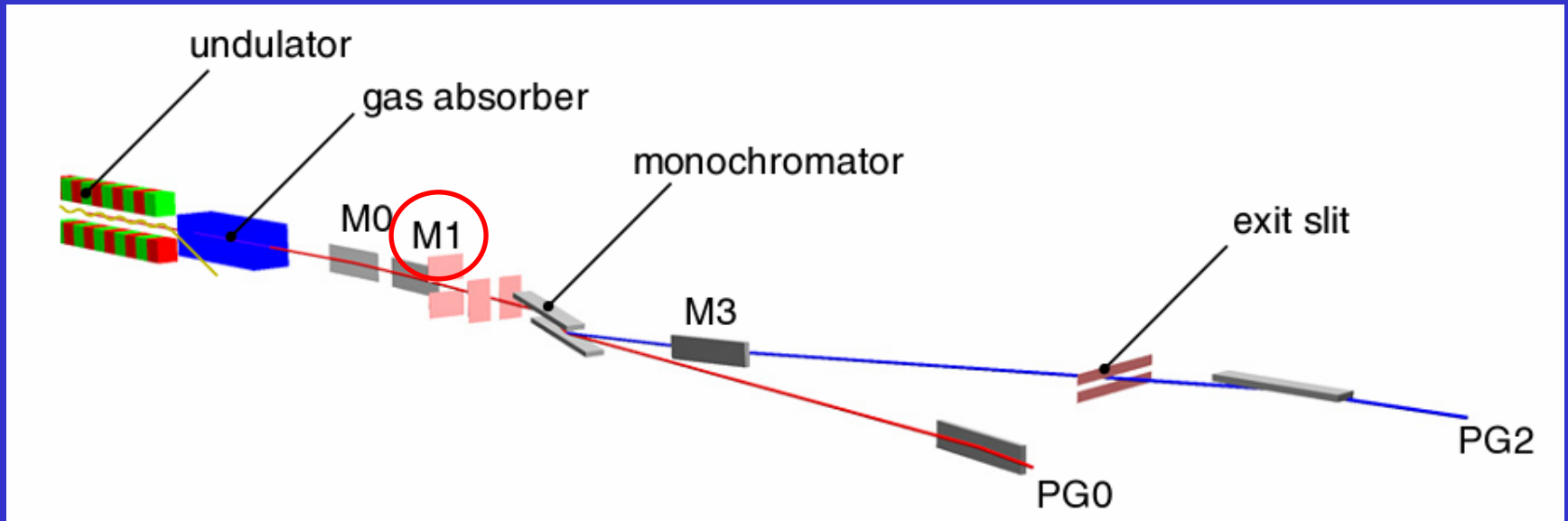
Setup for measurement of hard x-ray wave front distortions using a shearing interferometer (PSI)

Beamline PG2 (PG0) @ FLASH



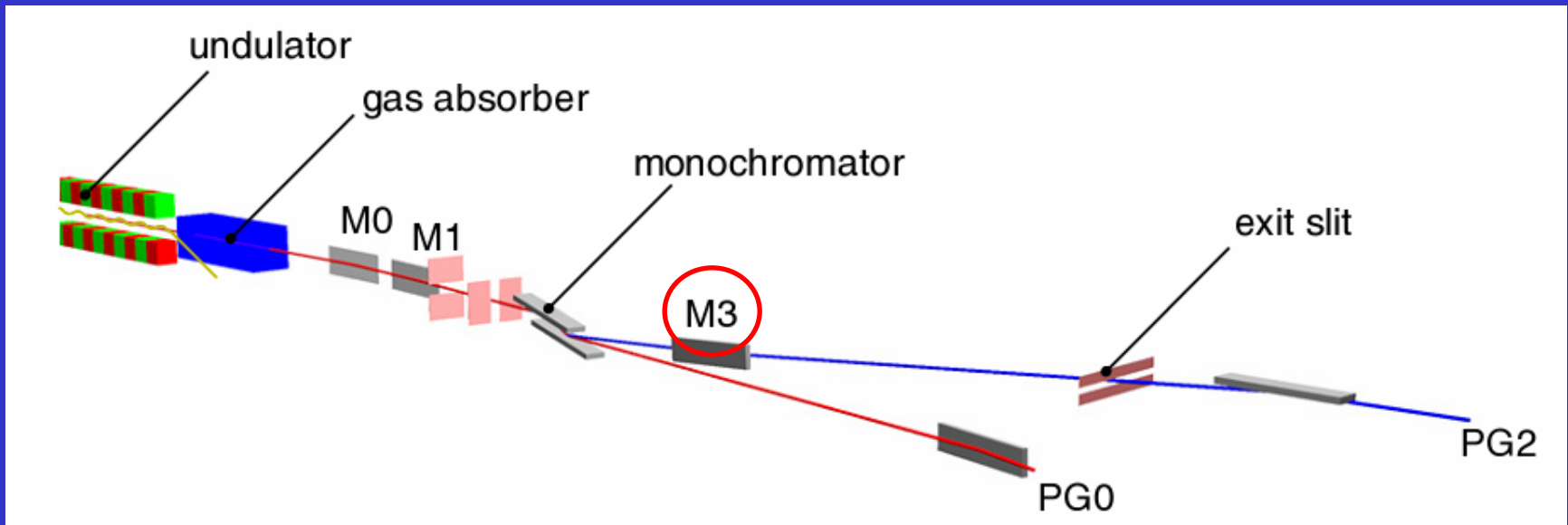
- Plane grating monochromator
- Two gratings: 200 lines/mm & 1200 lines /mm
- Optics are coated with diamond like carbon (DLC)

Beamline PG2 (PG0) @ FLASH



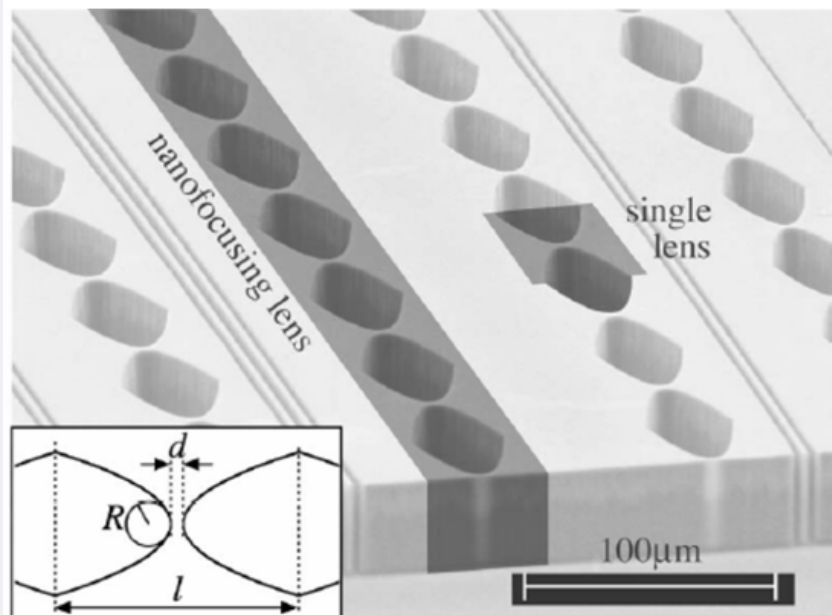
- Plane grating monochromator
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Beamline PG2 (PG0) @ FLASH



- Plane grating monochromator
- Two gratings: 200 lines/mm & 1200 lines /mm
- Optics are coated with diamond like carbon (DLC)

Focusing Optics



Nano-focusing Si lenses made
by electron beam lithography
C. Schroer (2005)



Diamond planar refractive
lenses fabricated using similar
technique

Detector requirements

- 2D detectors
- Dynamic range (10^5)
- 4K×4K, 10K ×10K plus
- Tiling or robot arm design
- Fast readout speed

Data acquisition: Computer requirements

Size	Memory needed	
	Single Precision	Double Precision
256^3	336 MB	592 MB
512^3	2.6 GB	4.6 GB
1024^3	21 GB	37 GB
2048^3	168 GB	296 GB

Size	32-CPU G5 cluster speed	
	3D FFT time	Time for 3D reconstruction
256^3	73 msec	10 min
512^3	850 msec	1.5 hrs
1024^3	7.9 sec	14 hrs
2048^3	-	-

*2000 iterations, 2 FFT's per iteration plus other floating point operations
code: C with mvapich, dist_fft (Altivec-optimized MPI FFT)
see http://images.apple.com/acg/pdf/20040827_GigaFFT.pdf

Summary

We want to use the full power of XFEL:

**Experimental realization of CXDI at
XFEL is straightforward and
community is ready to use XFEL for
coherent imaging
TODAY**

On femtosecond time scales

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- A. Mancuso (*HASYLAB*)
- O. Yefanov (*HASYLAB*)
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- J. Gulden (*HASYLAB*)
- R. Kurta (*HASYLAB*)

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- A. Zozulya (now at *EMBL, Hamburg*)

- **E. Weckert (*HASYLAB*)**
- *and many others ...*

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Thank you for your attention